

### **Excellent Integrated System Limited**

Stocking Distributor

Click to view price, real time Inventory, Delivery & Lifecycle Information:

Fairchild Semiconductor 74ABT16646CMTD

For any questions, you can email us directly: <u>sales@integrated-circuit.com</u>



### FAIRCHILD

SEMICONDUCTOR

October 1993 Revised November 1999

#### 74ABT16646 16-Bit Transceivers and Registers with 3-STATE Outputs

#### **General Description**

The ABT16646 consists of bus transceiver circuits with 3-STATE, D-type flip-flops, and control circuitry arranged for multiplexed transmission of data directly from the input bus or from the internal registers. Data on the A or B bus will be clocked into the registers as the appropriate clock pin goes to a high logic level. Control OE and direction pins are provided to control the transceiver function. In the transceiver mode, data present at the high impedance port may be stored in either the A or the B register or in both. The select controls can multiplex stored and real-time (transparent mode) data. The direction control determines which bus will receive data when the enable control  $\overrightarrow{OE}$  is Active LOW. In the isolation mode (control  $\overrightarrow{OE}$  HIGH), A data may be stored in the B register and/or B data may be stored in the A register.

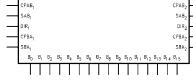
#### Features

- Independent registers for A and B buses
- Multiplexed real-time and stored data
- A and B output sink capability of 64 mA, source
- capability of 32 mA
- Guaranteed latchup protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Nondestructive hot insertion capability

#### **Ordering Code:**

Order Number	Package Number	Package Description				
74ABT16646CSSC	MS56A	56-Lead Shrink Small Outline Package (SSOP), JEDEC MO-118, 0.300" Wide				
74ABT16646CMTD	MTD56	56-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide				
Devices also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.						

## Logic Symbol



#### **Pin Descriptions**

Pin Names	Description
A <sub>0</sub> -A <sub>15</sub>	Data Register A Inputs/
	3-STATE Outputs
B <sub>0</sub> -B <sub>15</sub>	Data Register B Inputs/
	3-STATE Outputs
CPAB <sub>n</sub> , CPBA <sub>n</sub>	Clock Pulse Inputs
SAB <sub>n</sub> , SBA <sub>n</sub>	Select Inputs
OEn	Output Enable Input
DIR	Direction Control Input

#### **Connection Diagram**

DIR. 51 OF. CPAB, 55 - CPBA, - SBA SAB<sub>1</sub> 54 53 GND -- GND 52 An ₿'n 51 В1 A1 50 v<sub>cc</sub> • V<sub>CC</sub> Α2 49 48 • B<sub>2</sub> - 8, Α3 47 A<sub>4</sub> — B, 46 GND -- GNE 45  $A_5$ BS **4**4 A<sub>6</sub> -- B<sub>6</sub> A7 · 43 - B<sub>7</sub> A<sub>8</sub> · 42 41 - 8<sub>8</sub> 15 Ag 16 - Bg 40 A<sub>10</sub> 17 - B<sub>1</sub> 39 GND · - GND 18 38 A<sub>1.1</sub> — В, , 37 - B<sub>12</sub> A12 — B<sub>13</sub> 36 21 A<sub>13</sub> 35 34 Vcc 22 - v<sub>cc</sub> — В<sub>14</sub> A<sub>14</sub> 23 33 A.c 24 - B<sub>15</sub> 32 GND - GND 25 SAB<sub>2</sub> 31 — SBA<sub>2</sub> 26 30 CPAB<sub>2</sub> 27 СРВА DIR<sub>2</sub> 29 • OE<sub>2</sub> 28

© 1999 Fairchild Semiconductor Corporation DS011644



# 74ABT16646

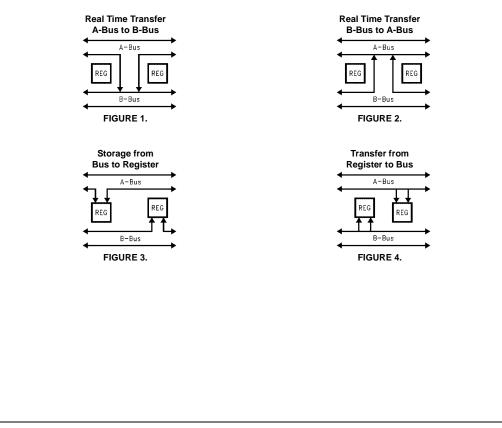
Inputs					Data I/O (Note 1)		Output Operation Mode	
OE <sub>1</sub>	DIR <sub>1</sub>	CPAB <sub>1</sub>	CPBA <sub>1</sub>	SAB <sub>1</sub>	SBA <sub>1</sub>	A <sub>0-7</sub>	B <sub>0-7</sub>	
Н	Х	H or L	H or L	Х	Х			Isolation
н	Х	~	Х	Х	Х	Input	Input	Clock An Data into A Register
Н	Х	Х	~	Х	Х			Clock Bn Data Into B Register
L	Н	Х	Х	L	Х			An to Bn—Real Time (Transparent Mode)
L	н	~	Х	L	Х	Input	Output	Clock An Data to A Register
L	н	H or L	Х	Н	Х			A Register to Bn (Stored Mode)
L	н	~	Х	н	Х			Clock An Data into A Register and Output to B
L	L	Х	Х	Х	L			Bn to An—Real Time (Transparent Mode)
L	L	Х	~	Х	L	Output	Input	Clock Bn Data into B Register
L	L	х	H or L	Х	Н			B Register to An (Stored Mode)
L	L	х	~	х	н			Clock Bn into B Register and Output to An

H = HIGH Voltage Level

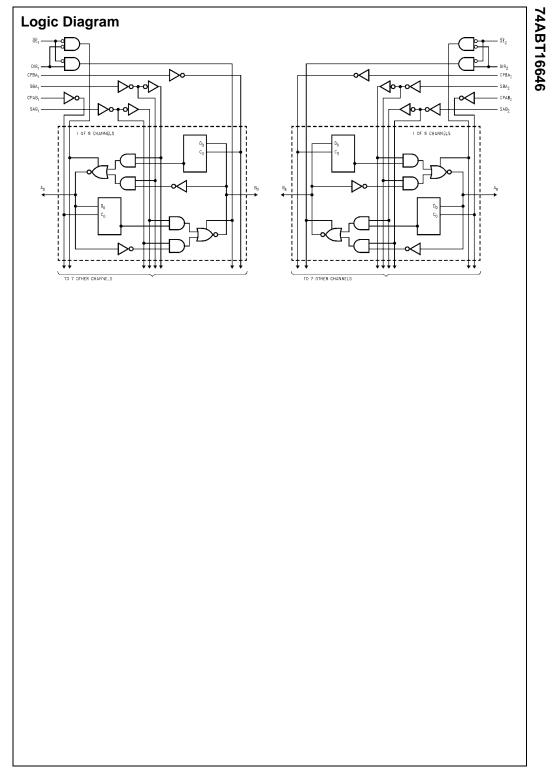
L = LOW Voltage Level

X = ImmaterialT = LOW-to-HIGH Transition

Note 1: The data output functions may be enabled or disabled by various signals at the  $\overline{OE}$  and DIR inputs. Data input functions are always enabled; i.e., data at the bus pins will be stored on every LOW-to-HIGH transition of the appropriate clock inputs. Also applies to data I/O (A and B: 8-15) and #2 control pins.









74ABT16646

Absolute Maximum F	Ratings(Note 2)	Recommended Operat	ing
Storage Temperature	-65°C to +150°C	Conditions	
Ambient Temperature under Bias	-55°C to +125°C	Free Air Ambient Temperature	-40°C to +85°C
Junction Temperature under Bias	-55°C to +150°C	Supply Voltage	+4.5V to +5.5V
V <sub>CC</sub> Pin Potential to Ground Pin	-0.5V to +7.0V	Minimum Input Edge Rate ( $\Delta V/\Delta t$ )	
Input Voltage (Note 3)	-0.5V to +7.0V	Data Input	50 mV/ns
Input Current (Note 3)	-30 mA to +5.0 mA	Enable Input	20 mV/ns
Voltage Applied to Any Output		Clock Input	100 mV/ns
in the Disable or		·	
Power-Off State	-0.5V to +5.5V		
in the HIGH State	-0.5V to V <sub>CC</sub>		
Current Applied to Output			
in LOW State (Max)	twice the rated I <sub>OL</sub> (mA)	Note 2: Absolute maximum ratings are values	beyond which the device
DC Latchup Source Current	–500 mA	may be damaged or have its useful life impa under these conditions is not implied.	ired. Functional operation
Over Voltage Latchup (I/O)	10V	Note 3: Either voltage limit or current limit is suff	icient to protect inputs.

#### **DC Electrical Characteristics**

Symbol	Parameter	Min	Тур	Max	Units	V <sub>CC</sub>	Conditions
V <sub>IH</sub>	Input HIGH Voltage	2.0			V		Recognized HIGH Signal
VIL	Input LOW Voltage			0.8	V		Recognized LOW Signal
V <sub>CD</sub>	Input Clamp Diode Voltage			-1.2	V	Min	I <sub>IN</sub> = -18 mA (Non I/O Pins)
V <sub>OH</sub>	Output HIGH Voltage	2.5					$I_{OH} = -3 \text{ mA}, (A_n, B_n)$
		2.0					$I_{OH} = -32 \text{ mA}, (A_n, B_n)$
V <sub>OL</sub>	Output LOW Voltage			0.55	V	Min	$I_{OL} = 64 \text{ mA}, (A_n, B_n)$
V <sub>ID</sub>	Input Leakage Test	4.75			V	0.0	$I_{ID} = 1.9 \ \mu\text{A}$ , (Non-I/O Pins)
							All Other Pins Grounded
I <sub>IH</sub>	Input HIGH Current			1	μA	Max	$V_{IN} = 2.7V$ (Non-I/O Pins) (Note 5)
				1	μΑ	IVIAA	$V_{IN} = V_{CC}$ (Non-I/O Pins)
I <sub>BVI</sub>	Input HIGH Current Breakdown Test			7	μΑ	Max	V <sub>IN</sub> = 7.0V (Non-I/O Pins)
I <sub>BVIT</sub>	Input HIGH Current Breakdown Test (I/O)			100	μA	Max	V <sub>IN</sub> = 5.5V (A <sub>n</sub> , B <sub>n</sub> )
Ι <sub>ΙL</sub>	Input LOW Current			-1	μA	Max	$V_{IN} = 0.5V$ (Non-I/O Pins) (Note 5)
				-1	μΛ	IVIGA	V <sub>IN</sub> = 0.0V (Non-I/O Pins)
$I_{\rm IH} + I_{\rm OZH}$	Output Leakage Current			10	μA	0V-5.5V	$V_{OUT} = 2.7V (A_n, B_n); \overline{OE} = 2.0V$
$I_{IL} + I_{OZL}$	Output Leakage Current			-10	μA	0V-5.5V	$V_{OUT} = 0.5V (A_n, B_n); \overline{OE} = 2.0V$
I <sub>OS</sub>	Output Short-Circuit Current	-100		-275	mA	Max	$V_{OUT} = 0V (A_n, B_n)$
I <sub>CEX</sub>	Output HIGH Leakage Current			50	μΑ	Max	$V_{OUT} = V_{CC} (A_n, B_n)$
I <sub>ZZ</sub>	Bus Drainage Test			100	μΑ	0.0V	$V_{OUT} = 5.5V (A_n, B_n);$
							All Others GND
I <sub>CCH</sub>	Power Supply Current			1.0	mA	Max	All Outputs HIGH
I <sub>CCL</sub>	Power Supply Current			60	mA	Max	All Outputs LOW
I <sub>CCZ</sub>	Power Supply Current			1.0	mA	Max	Outputs 3-STATE; All Others GND
I <sub>CCT</sub>	Additional I <sub>CC</sub> /Input			2.5	mA	Max	$V_I = V_{CC} - 2.1V$
							All Other Outputs at $V_{CC}$ or GND
I <sub>CCD</sub>	Dynamic I <sub>CC</sub> No Load				mA/	Max	Outputs OPEN
	(Note 5)			0.23	MHz		OE, DIR, and SEL = GND,
							Non-I/O = GND or V <sub>CC</sub> (Note 4)
							One Bit toggling, 50% duty cycle

Note 4: For 8-bit toggling, I<sub>CCD</sub> < 1.4 mA/MHz.

Note 5: Guaranteed but not tested.



#### **DC Electrical Characteristics**

Symbol	Parameter	Min	Тур	Max	Units	v <sub>cc</sub>	Conditions $\mathbf{C_L} = 50 \ \mathbf{pF}, \ \mathbf{R_L} = 500 \Omega$
V <sub>OLP</sub>	Quiet Output Maximum Dynamic V <sub>OL</sub>		0.7	1.2	V	5.0	T <sub>A</sub> = 25°C (Note 6)
V <sub>OLV</sub>	Quiet Output Minimum Dynamic V <sub>OL</sub>	-1.4	-1.0		V	5.0	T <sub>A</sub> = 25°C (Note 6)
V <sub>OHV</sub>	Minimum HIGH Level Dynamic Output Voltage	2.5	3.0		V	5.0	T <sub>A</sub> = 25° (Note 7)
V <sub>IHD</sub>	Minimum HIGH Level Dynamic Input Voltage	2.2	1.6		V	5.0	T <sub>A</sub> = 25°C (Note 8)
V <sub>ILD</sub>	Maximum LOW Level Dynamic Input Voltage		1.2	0.8	V	5.0	T <sub>A</sub> = 25°C (Note 8)

Note 6: Max number of outputs defined as (n). n - 1 data inputs are driven 0V to 3V. One output at LOW. Guaranteed, but not tested. Note 7: Max number of outputs defined as (n). n - 1 data inputs are driven 0V to 3V. One output HIGH. Guaranteed, but not tested.

Note 8: Max number of data inputs (n) switching. n – 1 inputs switching 0V to 3V. Input-under-test switching: 3V to threshold (V<sub>ILD</sub>), 0V to threshold (V<sub>ILD</sub>). Guaranteed, but not tested.

#### **AC Electrical Characteristics**

Symbol	Parameter	$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$			$T_{A} = -40^{\circ}0$ $V_{CC} = 4$ $C_{L} =$	Units	
		Min	Тур	Max	Min	Max	
f <sub>MAX</sub>	Maximum Clock Frequency		200				MHz
t <sub>PLH</sub>	Propagation Delay	1.5	3.0	4.9	1.5	4.9	ns
t <sub>PHL</sub>	Clock to Bus	1.5	3.4	4.9	1.5	4.9	115
t <sub>PLH</sub>	Propagation Delay	1.5	2.6	4.5	1.5	4.5	ns
t <sub>PHL</sub>	Bus to Bus	1.5	3.0	4.5	1.5	4.5	115
t <sub>PLH</sub>	Propagation Delay	1.5	2.9	5.0	1.5	5.0	ns
t <sub>PHL</sub>	SBA <sub>n</sub> or SAB <sub>n</sub> to A <sub>n</sub> to B <sub>n</sub>	1.5	3.2	5.0	1.5	5.0	115
t <sub>PZH</sub>	Enable Time	1.5	2.8	5.5	1.5	5.5	
t <sub>PZL</sub>	OE <sub>n</sub> to A <sub>n</sub> or B <sub>n</sub>	1.5	3.0	5.5	1.5	5.5	ns
t <sub>PHZ</sub>	Disable Time	1.5	3.9	6.0	1.5	6.0	
t <sub>PLZ</sub>	OE <sub>n</sub> to A <sub>n</sub> or B <sub>n</sub>	1.5	3.2	6.0	1.5	6.0	ns
t <sub>PZH</sub>	Enable Time	1.5	3.5	5.5	1.5	5.5	
t <sub>PZL</sub>	DIR <sub>n</sub> to A <sub>n</sub> or B <sub>n</sub>	1.5	3.2	5.5	1.5	5.5	ns
t <sub>PHZ</sub>	Disable Time	1.5	3.8	6.5	1.5	6.5	ns
t <sub>PLZ</sub>	DIR <sub>n</sub> to A <sub>n</sub> or B <sub>n</sub>	1.5	3.2	6.5	1.5	6.5	ns

#### AC Operating Requirements

Symbol	Parameter	V <sub>CC</sub>	+25°C = +5.0V 50 pF	$T_A = -40^{\circ}$ C to +85°C $V_{CC} = 4.5V-5.5V$ $C_L = 50 \text{ pF}$		Units
		Min	Max	Min	Max	
t <sub>S</sub> (H)	Setup Time, HIGH	2.0		2.0		ns
t <sub>S</sub> (L)	or LOW Bus to Clock	2.0		2.0		115
t <sub>H</sub> (H)	Hold Time, HIGH	1.0		1.0		ns
t <sub>H</sub> (L)	or LOW Bus to Clock	1.0		1.0		115
t <sub>W</sub> (H)	Pulse Width,	3.0		3.0		ns
t <sub>W</sub> (L)	HIGH or LOW	3.0		3.0		115

74ABT16646



# 74ABT16646

		T <sub>A</sub> = −40°C to +85°C V <sub>CC</sub> = 4.5V−5.5V		T <sub>A</sub> = -40°C to +85°C V <sub>CC</sub> = 4.5V-5.5V		$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$ $V_{CC} = 4.5V - 5.5V$		
Symbol	ol Parameter	<b>C</b> <sub>L</sub> =	50 pF	C <sub>L</sub> = 2	250 pF	C <sub>L</sub> = 2	250 pF	Units
Symbol	Falanetei	8 Outputs	Switching	1 Output	Switching	8 Outputs	Switching	
		(Note 9)		(Note 10)		(Note 11)		
		Min	Max	Min	Max	Min	Max	
t <sub>PLH</sub>	Propagation Delay	1.5	5.8	2.0	7.5	2.5	10.0	ns
t <sub>PHL</sub>	Clock to Bus	1.5	5.8	2.0	7.5	2.5	10.0	115
t <sub>PLH</sub>	Propagation Delay	1.5	6.5	2.0	7.0	2.5	9.5	
t <sub>PHL</sub>	Bus to Bus	1.5	6.5	2.0	7.0	2.5	9.5	ns
t <sub>PLH</sub>	Progagation Delay	1.5	6.0	2.0	7.5	2.5	10.0	
t <sub>PHL</sub>	$SBA_{n} \text{ or } SAB_{n} \text{ to } A_{n} \text{ or } B_{n}$	1.5	6.0	2.0	7.5	2.5	10.0	ns
t <sub>PZH</sub>	Output Enable Time	1.5	6.0	2.0	8.0	2.5	10.5	
t <sub>PZL</sub>	OE <sub>n</sub> to A <sub>n</sub> or B <sub>n</sub>	1.5	6.0	2.0	8.0	2.5	10.5	ns
t <sub>PHZ</sub>	Output Disable Time	1.5	6.0	(A.L.)	(0)		10)	
t <sub>PLZ</sub>	OE <sub>n</sub> to A <sub>n</sub> or B <sub>n</sub>	1.5	6.0	(Not	e 12)	(Note	ə 12)	ns
t <sub>PZH</sub>	Output Enable Time	1.5	6.5	2.0	8.0	2.5	10.5	
t <sub>PZL</sub>	DIR to A <sub>n</sub> or B <sub>n</sub>	1.5	6.5	2.0	8.0	2.5	10.5	ns
t <sub>PHZ</sub>	Output Disable Time	1.5	6.5	(N lat	- 10)	(Nint)	. 40)	
t <sub>PLZ</sub>	DIR to An or Bn	1.5	6.5	(NOT	e 12)	(Note 12)		ns

Note 9: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.).

Note 10: This specification is guaranteed but not tested. The limits represent propagation delay with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load. This specification pertains to single output switching only.

Note 11: This specification is guaranteed but not tested. The limits represent propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.) with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load.

Note 12: The 3-STATE delays are dominated by the RC network (500Ω, 250 pF) on the output and has been excluded from the datasheet.



Symbol	Parameter	Parameter $T_{A} = -40^{\circ}C \text{ to } +85^{\circ}C$ $V_{CC} = 4.5V - 5.5V$ $C_{L} = 50 \text{ pF}$ 16 Outputs Switching (Note 13)		Units	
t <sub>OSHL</sub> (Note 15)	Pin to Pin Skew HL Transitions	2.0	<b>Max</b> 2.5	ns	
t <sub>OSLH</sub> (Note 15)	Pin to Pin Skew LH Transitions	2.0	2.5	ns	
t <sub>PS</sub> (Note 16)	Duty Cycle LH–HL Skew	2.0	2.5		
t <sub>OST</sub> (Note 15)	Pin to Pin Skew LH/HL Transitions	2.8	3.0	ns	
t <sub>PV</sub> (Note 17)	Device to Device Skew LH/HL Transitions	3.5	4.0	ns	

Note 13: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase

(i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.).

Note 14: This specification is guaranteed but not tested. The limits represent propagation delays with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load.

Note 15: Skew is defined as the absolute value of the difference between the actual propagation delays for any two separate outputs of the same device. The specification applies to any outputs switching HIGH to LOW ( $t_{OSHL}$ ), LOW to HIGH ( $t_{OSLH}$ ), or any combination switching LOW to HIGH and/or HIGH to LOW ( $t_{OST}$ ). This specification is guaranteed but not tested.

Note 16: This describes the difference between the delay of the LOW-to-HIGH and the HIGH-to-LOW transition on the same pin. It is measured across all the outputs (drivers) on the same chip, the worst (largest delta) number is the guaranteed specification. This specification is guaranteed but not tested. Note 17: Propagation delay variation for a given set of conditions (i.e., temperature and V<sub>CC</sub>) from device to device. This specification is guaranteed but not tested.

#### Capacitance

Symbol	Parameter	Тур	Units	Conditions $T_A = 25^{\circ}C$
C <sub>IN</sub>	Input Capacitance	5	pF	V <sub>CC</sub> = 0V (non I/O pins)
C <sub>I/O</sub> (Note 18)	Output Capacitance	11	pF	$V_{CC} = 5.0V (A_n, B_n)$

Note 18:  $C_{I/O}$  is measured at frequency, f = 1 MHz, per MIL-STD-883, Method 3012.



